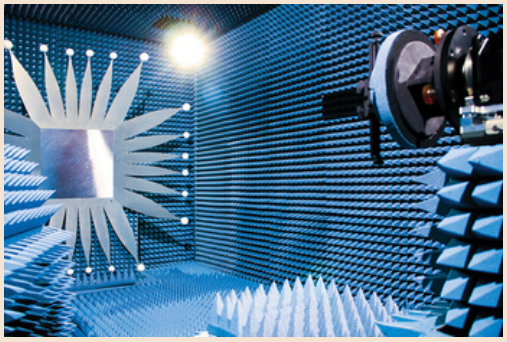
Emerging 5G Test Methodologies to Efficiently and Cost-Effectively Validate Antenna Performance



Abstract

Speakers will address emerging test methodologies to efficiently and cost effectively validate antenna performance in a design lab environment. The significance of different test methods will be shown using near-field, far-field, and alternative test techniques. Attendees will learn about modern 5G millimeter wave antenna array evaluation in near- and far-field environments, important measurement uncertainty considerations in the performance validation test set up, and the latest regulatory and measurement challenges with the new Wi-Fi 7 enabled devices.

Speakers

Janet O'Neil is a customer relations specialist with ETS-Lindgren. She has over 30 years of experience in the RF and Electromagnetic Compatibility (EMC) industries. She is a member of the Board of Directors of the IEEE EMC Society and past member of the Antenna Measurement Techniques Association (AMTA) Board of Directors. Ms. O'Neil has organized dozens of technical workshops during her career as well as served as chair or vice-chair of various IEEE International Symposiums for the EMC and MTT Societies. Her education includes BA degrees in English and in Business Economics from the University of California, Santa Barbara.

Aurelian Bria works at Ericsson AB in Kista in the standardization and regulation group since 2008. For more than 15 years he was a representative of Ericsson in 3GPP RAN WG4 with significant contributions in base station RF requirements and Over-the-Air test methodologies. He is also member of ETSI MSG Task Force for European Standard and a contributor to the development of C63.26 standard under American National Standard Committee C63. Aurelian holds a Master of Science degree from Politehnica University in Bucharest and a Ph.D. in Radio Communication Systems from the Royal Institute of Technology in Stockholm.

Juan Antonio del Real is the Sales Director for EMEA at Maury Microwave, a global leader in RF and microwave measurement solutions. He holds a degree in Electronics Engineering from ITESO, Mexico, and specialized in RF Systems Engineering at Paul Sabatier University, France. With a distinguished career in the RF and microwave industry, Juan has held key positions at leading companies such as Intel, Rohde & Schwarz, and Sigfox, gaining extensive expertise in test and measurement solutions for aerospace, defense, telecommunications, and quantum computing applications. With a strong background in technical sales and applications engineering, Juan has collaborated with top research institutions, defense contractors, and commercial enterprises to optimize RF performance through advanced calibration, load pull, and measurement automation techniques. His areas of expertise include phase noise analysis, impedance tuning, high-power RF characterization, and state-of-the-art signal generation. Juan is an active contributor to the RF and microwave community, frequently presenting at industry conferences and publishing technical papers on RF measurement techniques.

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Speakers

James Young is the Director, Wireless Systems, with ETS-Lindgren. He is responsible for researching industry and customer requirements and then building solutions to meet them. With a focus on new products and partnerships targeting wireless, EMC, and medical industries, Mr. Young seeks out customer feedback and solution user conversations. He has spent over 20 years selling, designing, and installing wireless and EMC test systems. Prior to joining ETS-Lindgren, Mr. Young worked at AMETEK CTS and Rohde & Schwarz in various engineering, sales, and marketing positions.His engineering background includes system, ASIC, and FPGA design for various communication, wireless, and RF test products. Mr. Young holds a BSEET from Weber State University and an MBA from the University of Phoenix.

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